

Amendments to the Specification:

Please amend the Title of the invention as shown below:

**RADIATION DETECTOR WITH HIGH LINEARITY AND SENSITIVITY
FOR LOW RADIATION RADIOGRAPHY, PHOTOMETRY, DOSIMETRY
AND IONIZING-RADIATION FIELDS**

Please amend paragraph 0022 beginning on page 16, line 10 as shown below:

In multi-element modifications of the detector (see Figs. 2, 3, 6, [[6]] 7), the interrogation pulse generator 1 is provided with a plurality of outputs, with voltage pulses forming on each of them in a preset sequence. In this case, a serial interrogation of switching-type transistors 3, which are included into the groups of elements 8, corresponding, for example, to a sequential reading out of the respective integrating capacitors 7, is performed, while a sequence of current pulses, displayed as video signals, form at the load 4, when synchronizing clock is added thereto at the respective instant of time. It should be noted that the coordinate of the detector sensitive element is uniquely defined by the number of the load pulse corresponding thereto or by the time said pulse is generated, while the number of radiation particles detected in said sensitive element is defined by the amplitude of the current pulse corresponding thereto. In the detector modifications having a plurality of loads (see Figs 3, 7), the sequence of interrogation current pulses forms serially at each load at time intervals of interrogation of switching-type transistors incorporated into the groups of elements 8 coupled with said load. Availability of a plurality of loads in the detector allows the total number of sensitive elements to be increased in the detector without increasing the noise of amplifier integrating capacitors detecting the readout signals. In addition to the increased radiation detector sensitivity, the capability of the detector being provided to analyze space-energy characteristics of various types of radiation fields to be detected within an extensive intensity range significantly expands functional capacities and application field thereof. The invention may be used in the fields of nuclear physics, dosimetry, radiation flaw inspection, photometry, crystallography, medicine and other fields of science and engineering.